"Real-time millikelvin thermometry in a semiconductor-qubit architecture

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We report local time-resolved thermometry in a silicon-nanowire quantum dot device designed to host a linear array of spin qubits. Using two alternative measurement schemes based on rf reflectometry, we are able to probe either local electron or bosonic bath temperatures with microsecond time scale resolution and a noise-equivalent temperature of $3 \text{ mK}/\sqrt{\text{Hz}}$. Following the application of short microwave pulses, causing local periodic heating, time-dependent thermometry can track the dynamics of thermal excitation and relaxation, revealing clearly different characteristic time scales. This work opens important prospects to investigate the out-of-equilibrium thermal properties of semiconductor quantum electronic devices operating at very low temperature. In particular, it may provide a powerful handle to understand heating effects recently observed in semiconductor spin-qubit systems.

Motivation







RF reflectometry with LC resonator

Fitting amplitude of reflected signal

$$S_{21,dB} = 20 \log \left| 1 + \frac{Q_{i} e^{i\varphi}}{Q_{c} \left[1 + 2iQ_{i} \left(\frac{f - f_{r}}{f_{r}} \right) \right]} \right|$$

At 52 mK:

$$Q_i = 385$$

 $Q_c = 62$
 $Q = Q_i // Q_c = 53.4$

 $S_{21,dB}$ amplitude in dB of reflected signal Q_i internal quality factor Q_c external quality factor

Time resolution limit ~
$$\tau = \frac{Q}{2\pi f_0} = 20$$
 ns @ $f_0 = 400$ MHz

Quantum capacitance, dot-lead situation

$$C_{q}(\varepsilon) = \alpha^{2} e^{2} [f * g](\alpha e \varepsilon)$$

 $f(E) = \frac{1}{4k_{\rm B}T_{\rm e}} \cosh\left(\frac{E}{4k_{\rm B}T_{\rm e}}\right)^{-2}$

Derivative of Fermi distribution in the lead broadened by $k_{\rm B}T_{\rm e}$

 α gate lever-arm parameter

- ε detuning in gate voltage
- \varGamma tunnelling rate between dot and lead (angular frequency)
- $T_{\rm e}$ electron temperature in the lead

e electron charge $k_{\rm B}$ Boltzmann constant \hbar reduced Planck constant) Dot density of states modeled by Lorentzian of width $\hbar\Gamma$

 $g(E) = \frac{\hbar\Gamma}{(\hbar\Gamma)^2 + E^2}$

Regime: $\hbar \Gamma < k_{\rm B} T_{\rm e}$



Quantum capacitance, double dot situation

$$C_{q}(\varepsilon) = \alpha^{2}e^{2} \frac{2t^{2}}{\left((\alpha\varepsilon\varepsilon)^{2} + 4t^{2}\right)^{3/2}} \tanh\left(\frac{\left((\alpha\varepsilon\varepsilon)^{2} + 4t^{2}\right)^{1/2}}{2k_{B}T_{B}}\right)$$
where $k_{B}T_{B} = \frac{2t}{\ln\left(\frac{P_{|+|}}{P_{|-|}}\right)}$
Regime: $t \leq k_{B}T_{B}$
From Boltzmann distribution on two states
 t tunnel coupling between the two dots (energy)
 $P_{|+|}$ and $P_{|-|}$ populations of $|+|$ or $|-|$ states
(hybridised (bonding and antibonding) states, at detuning $\varepsilon = 0$)
 e electron charge

 ε

 $k_{\rm B}$ Boltzmann constant \hbar reduced Planck constant)

Preliminary checks and setup: LC resonator





Preliminary checks and setup: temperature sensitive regime for double quantum dot, with low tunnel coupling (setting II) $t/h = 2.03 \pm 0.04$ GHz



FIG. S3. Isolated double dot charge stability diagram. (a) Charge stability diagram showing 'infinite' interdot transitions. (b) Peak amplitude and width as a function of the gate voltage, showing a way to reduce the tunnel coupling.







Calibration of double quantum dot thermometer: reflected signal phase at zero detuning ($\epsilon = 0$)



Noise-equivalent temperature

Expression of noise-equivalent temperature:





FIG. S4. Noise spectrum. a) Power spectrum computed using Welchs'method⁹, showing a white noise spectrum with a noise floor $S_P = 1.03 \pm 0.09 \times 10^{-11} \text{V}^2$. b) Phase spectral density, showing a white noise spectrum with a noise floor $S_{\varphi\varphi} = 3.9 \pm 0.2 \text{ mrad}/\sqrt{\text{Hz}}$ $S_{\varphi\varphi} = 3.9 \pm 0.2 \text{ mrad}/\sqrt{\text{Hz}}$ is the phase-noise amplitude

In the region of maximum sensitivity (temperature close to base temperature ~55 mK)

NET =
$$3.0 \pm 0.2 \text{ mK}/\sqrt{\text{Hz}}$$
 (with $\left|\frac{\partial \varphi_0}{\partial T_{\text{MC}}}\right| = 1.28 \text{ mrad}/\text{mK}$ fitted in previous plot)

Could be improved with better impedance matching

Noise-equivalent temperature

Starting from the expression of reflected signal phase at zero detuning fitted previously

$$\varphi_0 = \kappa \times \frac{1}{2t} \tanh\left(\frac{t}{k_{\rm B}T_{\rm MC}}\right))$$

Assuming dispersive coupling between the *LC* resonator and the isolated double quantum dot implies:

$$\kappa = A_0 \left(\frac{1}{2t + f_r} + \frac{1}{2t - f_r} \right)$$

Resonance frequency of "tank" circuit

Now *t* is used as parameter and the expression the NET = $\frac{S_{\varphi\varphi}}{\left|\frac{\partial\varphi_0}{\partial T_{MC}}\right|}$ can be calculated at various *t*



"Real-time" thermometry (proof of concept)

- Noise-equivalent temperature is too large to resolve temperature fluctuations at microsecond scale
- But noise can be reduced with averaging if heating event is periodic or deterministic/reproducible
- For example, microwave bursts used for operation of spin-qubit devices

Limiting bandwidths

- Response time of measurement apparatus (~ 20 ns)
- Charge relaxation time T1 toward a thermal state (~ 15 ns)

Hence few MHz resolution

Proof of concept: periodic microwave burst on nearby gate (20 kHz) 15 GHz 15 GHz -40 dBm -40 dBm Lockin parameters: 1.7 MHz 50 µs 400 ns integration 50 µs 50 µs 50 µs window O MW on MW off 220 \varphi_c 55 mK Slow exponential 215 φ_h $\varphi_0 \;(\mathrm{mrad})$ 62 mKdecay ($\tau = 67.0 \pm$ 1.5 µs): relaxation 210 of the heat bath? Fast exponential 205 Exponential decay decay: T1 relaxation? τ = 0.93 ± 0.35 μs $\varphi_{on} = - \varphi_{on}$ 75 mK 200 (too short) 30 10 20 10 20 0 Time (μs) Time (μs) 18

Conclusion and outlook

- "Noninvasive, nongalvanic thermometers"
- Both Fermi reservoir (dot-lead setting) and local bosonic temperature in semiconductor quantum dot (double quantum dot setting)
- State-of-the-art noise-equivalent temperature of $3 \text{ mK}/\sqrt{\text{Hz}}$
- Temperature variations measured on microsecond scale when averaging is possible
- Technique demonstrated in silicon MOS device, could be applied on other platforms: Si-Ge-based heterostructures?



FIG. S4. Noise spectrum. a) Power spectrum computed using Welchs'method⁹, showing a white noise spectrum with a noise floor $S_P = 1.03 \pm 0.09 \times 10^{-11} \text{V}^2$. b) Phase spectral density, showing a white noise spectrum with a noise floor $S_{\varphi\varphi} = 3.9 \pm 0.2 \text{ mrad}/\sqrt{\text{Hz}}$

The two quadratures of the demodulator I and Q are measured for different sampling frequencies to access noise spectrum in a wide frequency range. From the noise floor we can access to the noise temperature NT:

$$NT = \frac{S_P}{10^{\frac{G_{dB}}{10}} B \times 4k_B R} \tag{S16}$$

Where S_P is the noise floor, G_{dB} is the gain in dB of the room temperature amplifier, B is the bandwidth of the demodulator and R is the 50 Ω -impedance of the transmission line. We find a $NT = 1.9 \pm 0.3$ K, where as the cryogenic amplifier (LNF-LNC 0.2-3 A s/n 1410Z) used in this experiment has a noise temperature of around 2 K